

# HGCROCV2 for ALICE FoCal

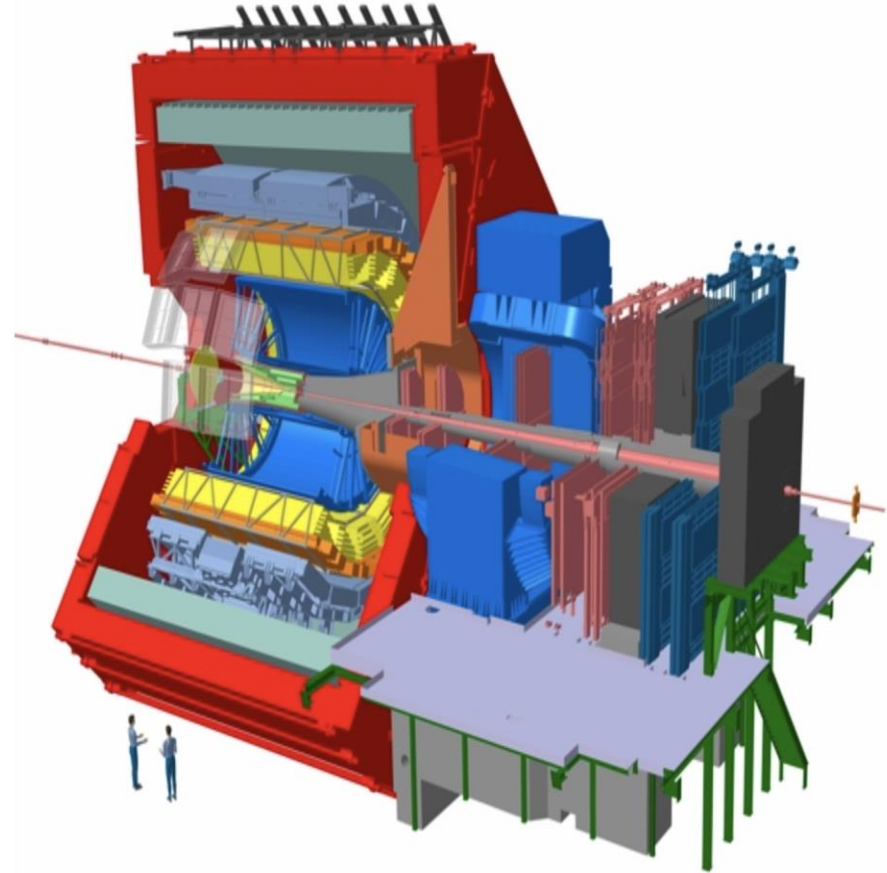
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(Saga University)

Saga-Yonsei Joint Workshop, Nov 5, 2024

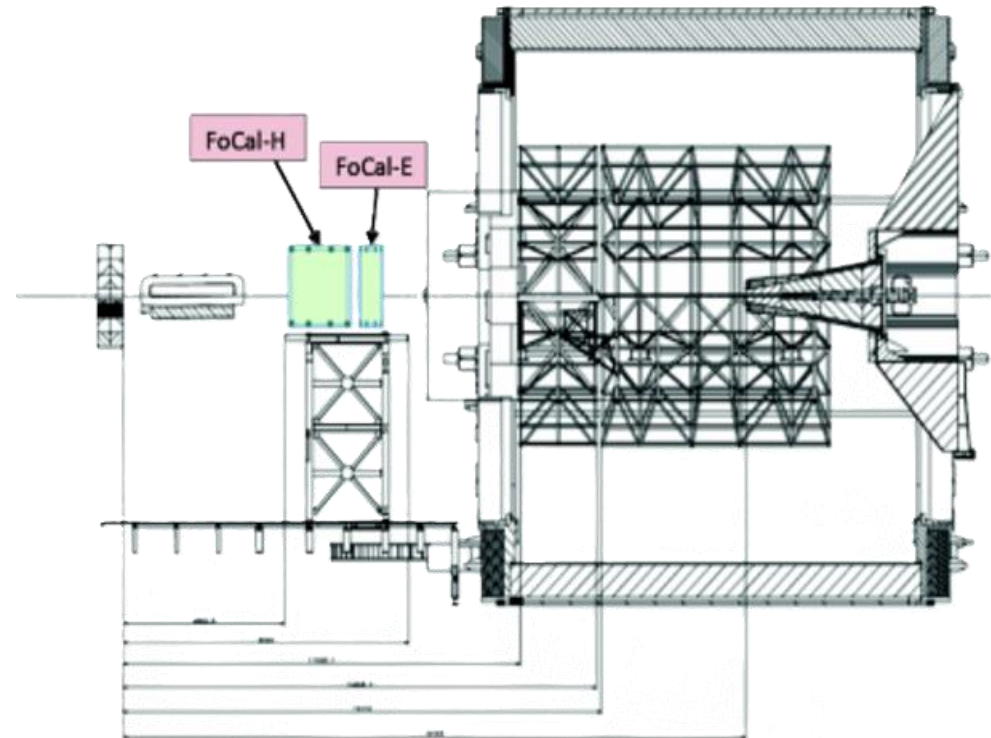
# ALICE(A Large Ion Collider Experiment)

- The heavy-ion collision experiment using the Large Hadron Collider (LHC) at the European Organization for Nuclear Research (CERN).
- Purpose  
To recreate and understand the properties of quark-gluon plasma (QGP), a state of matter believed to have existed in the early universe.



# ALICE FoCal

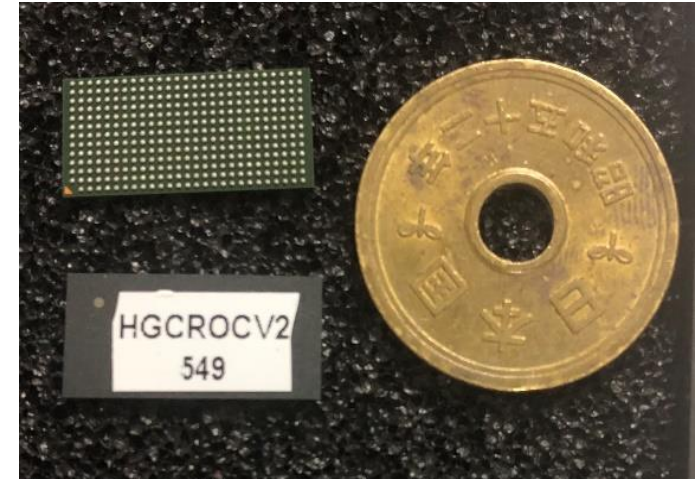
- Upgrade plans for the ALICE experiment.
- Focal = Forward Calorimeter
- It will be installed in the forward region of the heavy-ion collision point to measure areas that have not been accessible before.



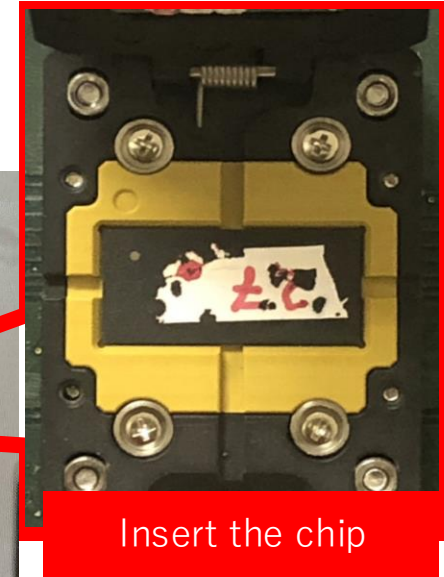
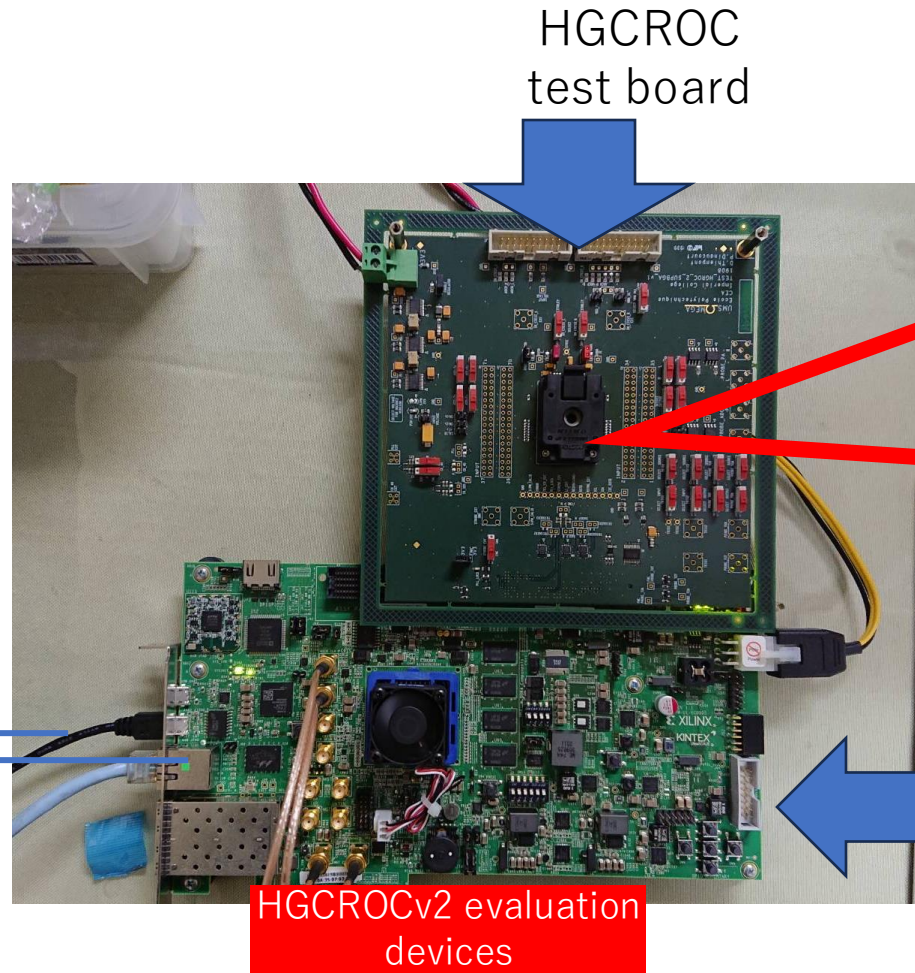
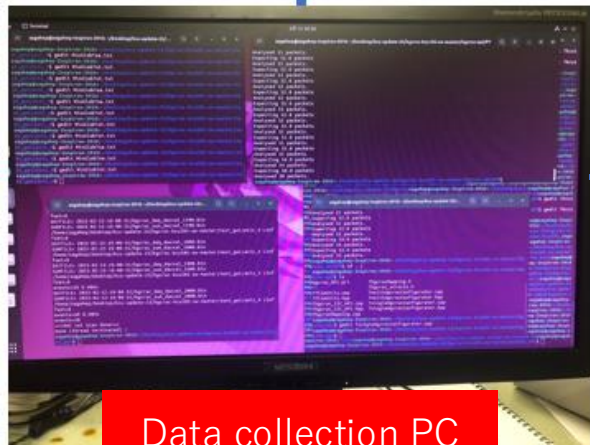
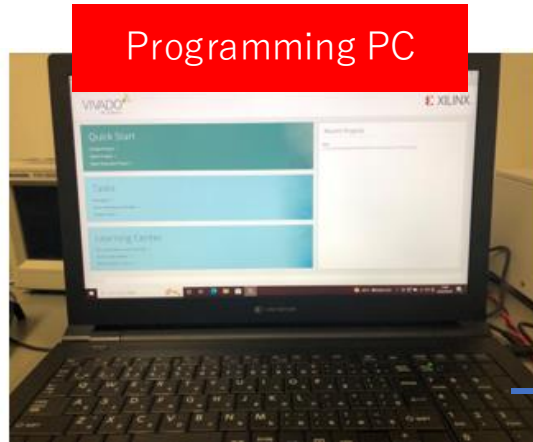
# HGCROCv2

High Granularity Calorimeter Read Out Chip version2

- The integrated circuit chip used for data acquisition in the ALICE experiment.
- High radiation tolerance
- HGCROCv1 : Prototype
- HGCROCv2 : Channel count increased to 72ch
  - 36 standard ADC channels
  - + 36 experimental ADC channels
- HGCROCv3 : Final version



# Measurement device



XILINX FPGA KCU105

# HGCROCv2

- ADC The signal pulse height obtained in the low-energy range.
- ToA(Time to Arrival)  
The time information at which the set threshold was reached.
- ToT(Time over Threshold)  
Indicates the difference between the time when the preset threshold was reached and the Time of Arrival (ToA).

# Performance Evaluation of HGCROCV2

- The performance is evaluated by assessing whether linearity is maintained with respect to the magnitude of the acquired energy in the processing of ADC and ToT.
- Eventually, we will evaluate the properties of several hundred HGCROCV2 chips and make adjustments to various parameters with the aim of completing the HGCROC.

# ADC and ToT Measurement Range

ADC → Measures charge range from 0 to 160 fC.

ToT → Measures charge range from 160fC to 10pC

The ADC enters a saturated state at a certain input charge level, and instead, the ToT is used for measurement.

Is the linearity maintained between the ADC and ToT?

Is measurement proportional to the amount of input charge possible?

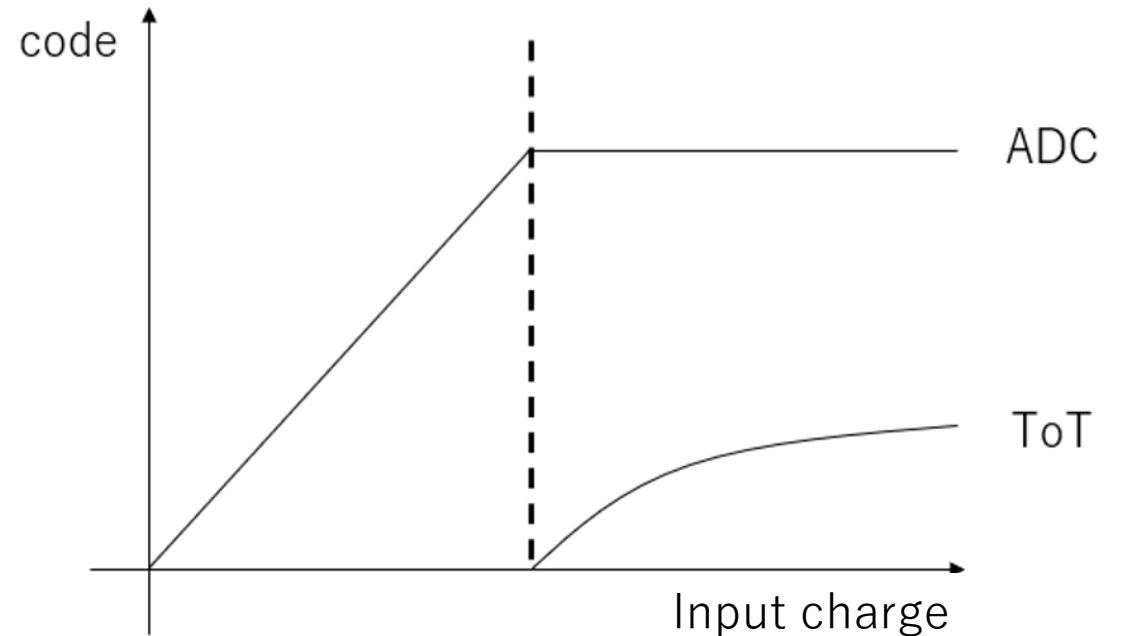


Image Diagram



# Actual measurement

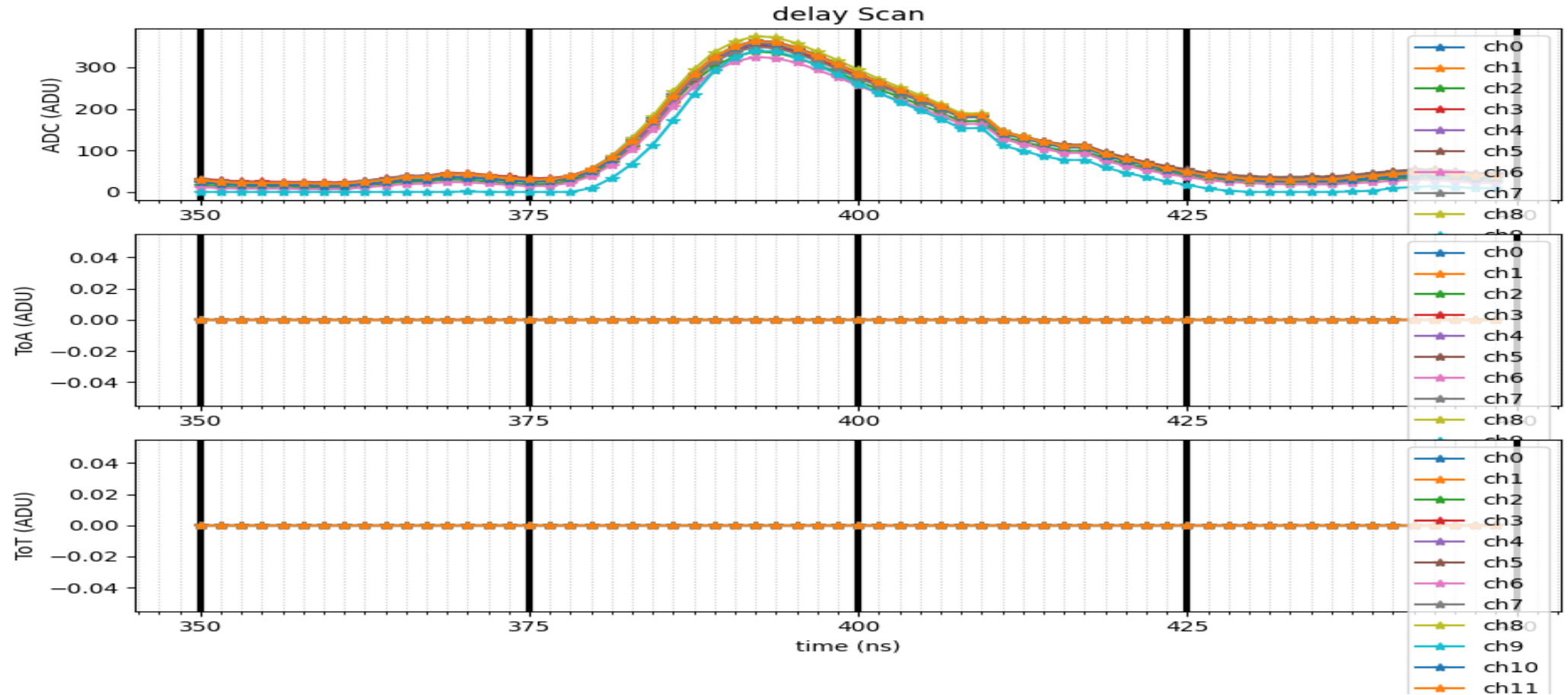
- 12 chips measurements
- 10 chips do not move  
No delay, error, etc

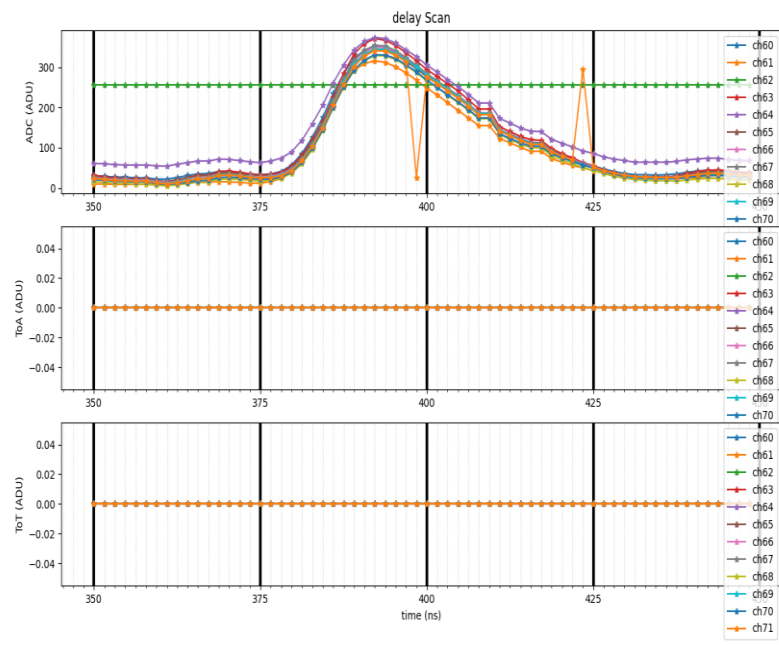
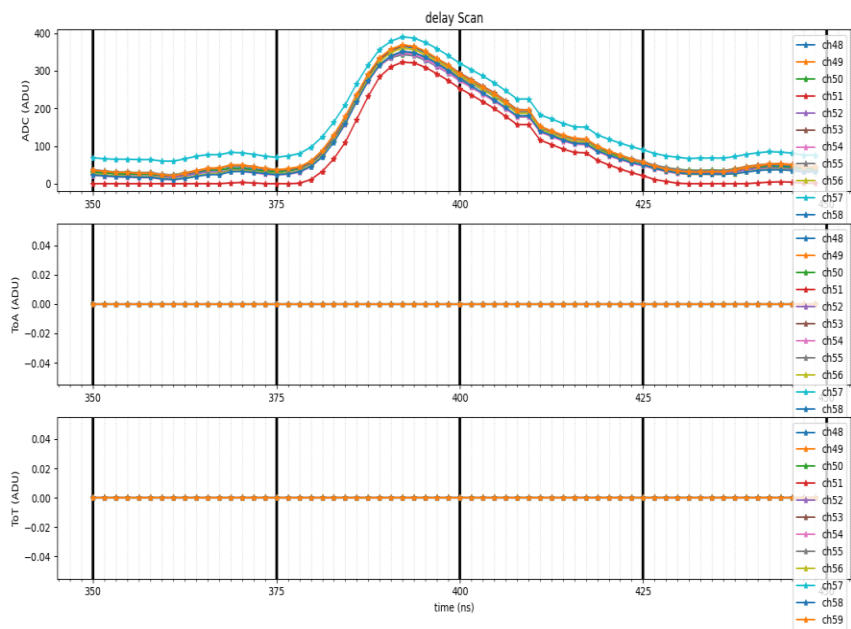
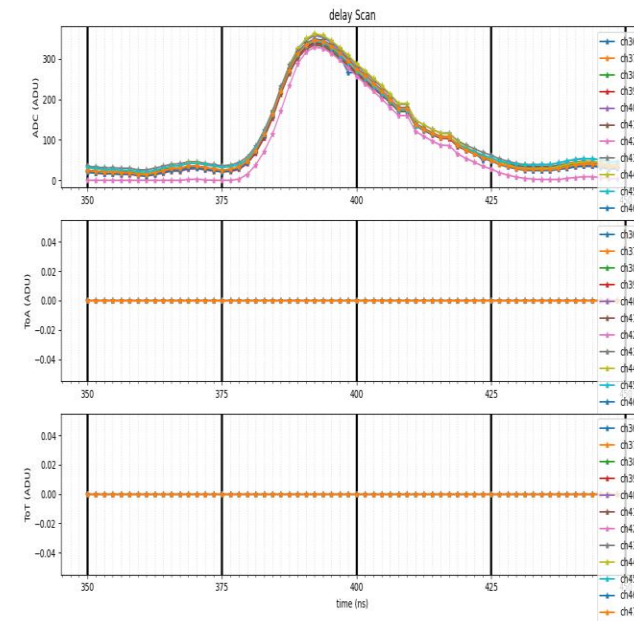
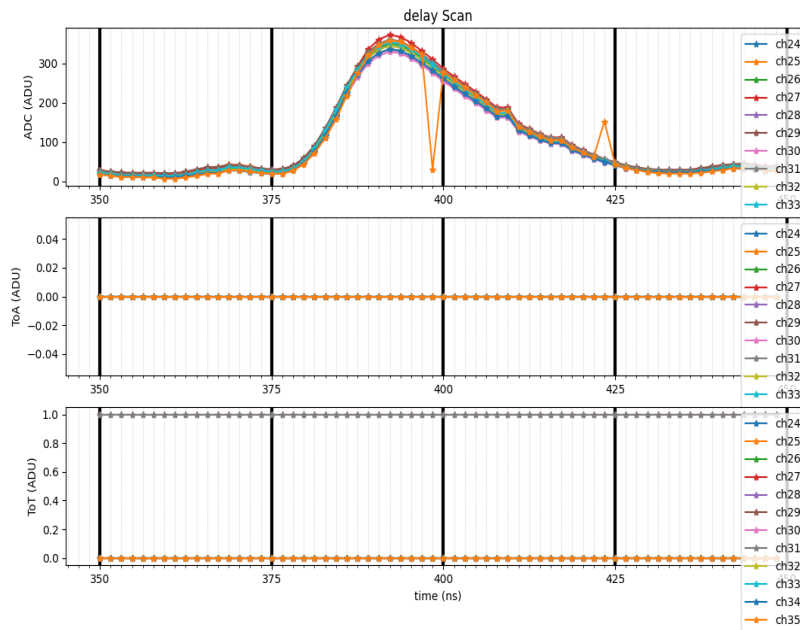
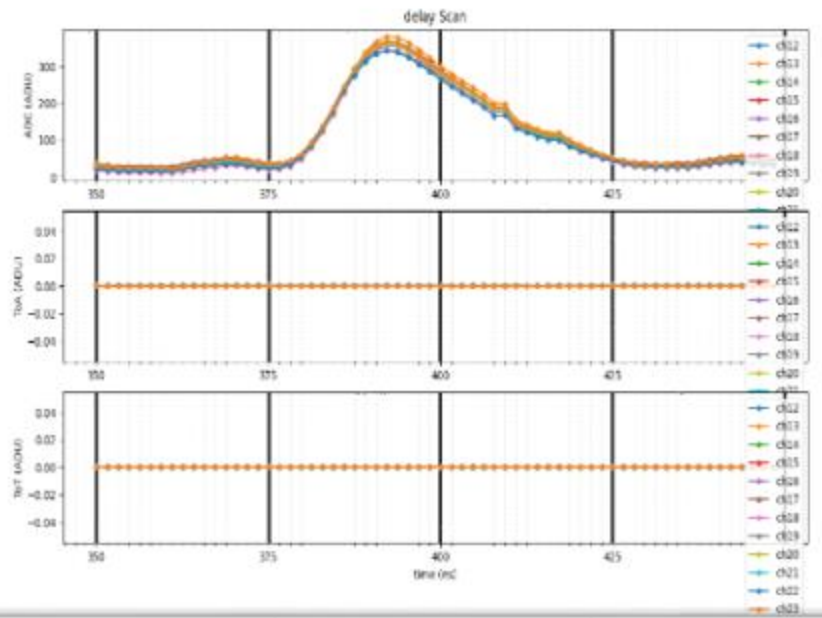
Cause: Is the chip faulty?

Will it work with a different firmware?

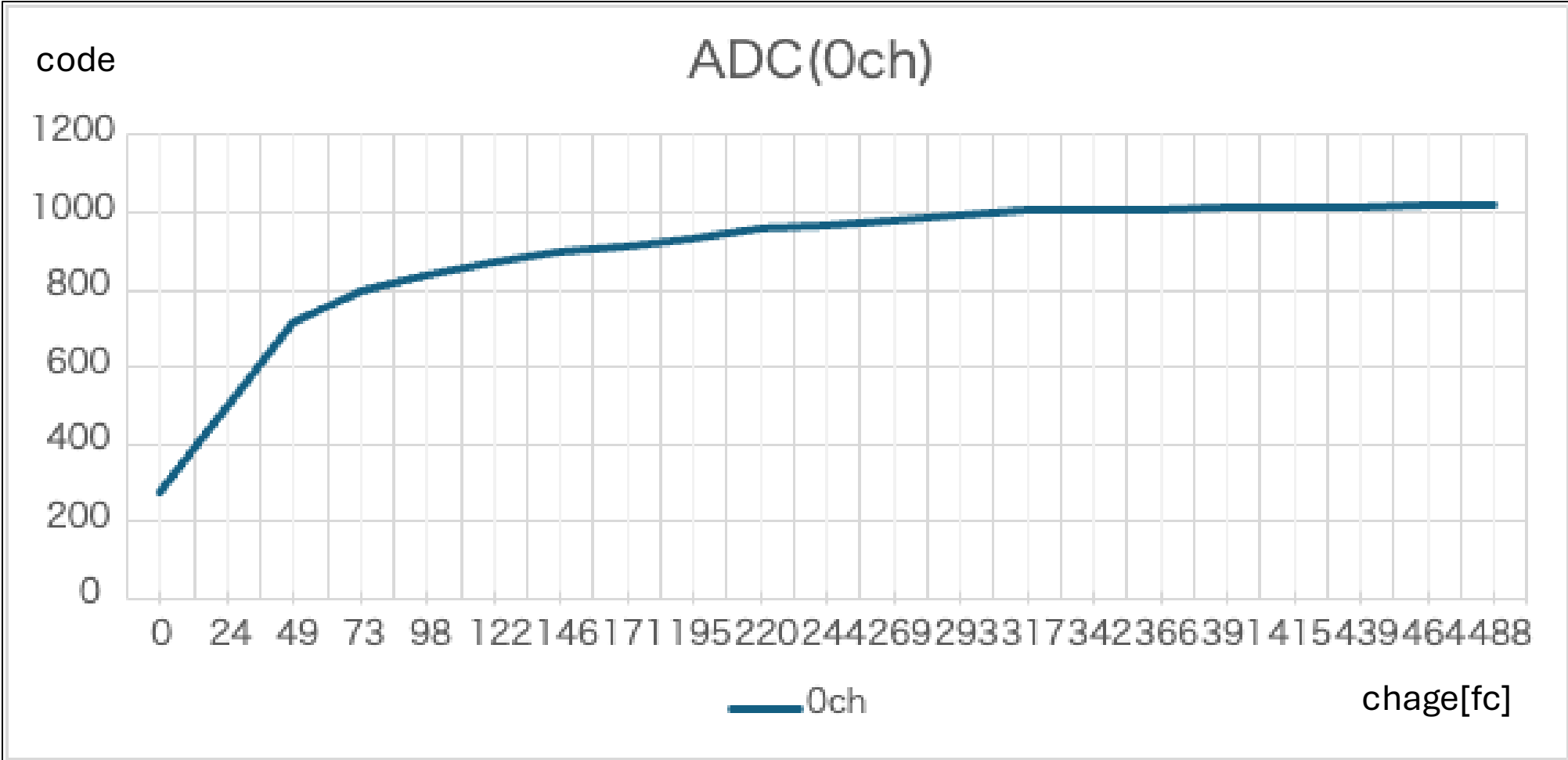
I don't fully understand it right now

# Example of measurement data(DelayScan)

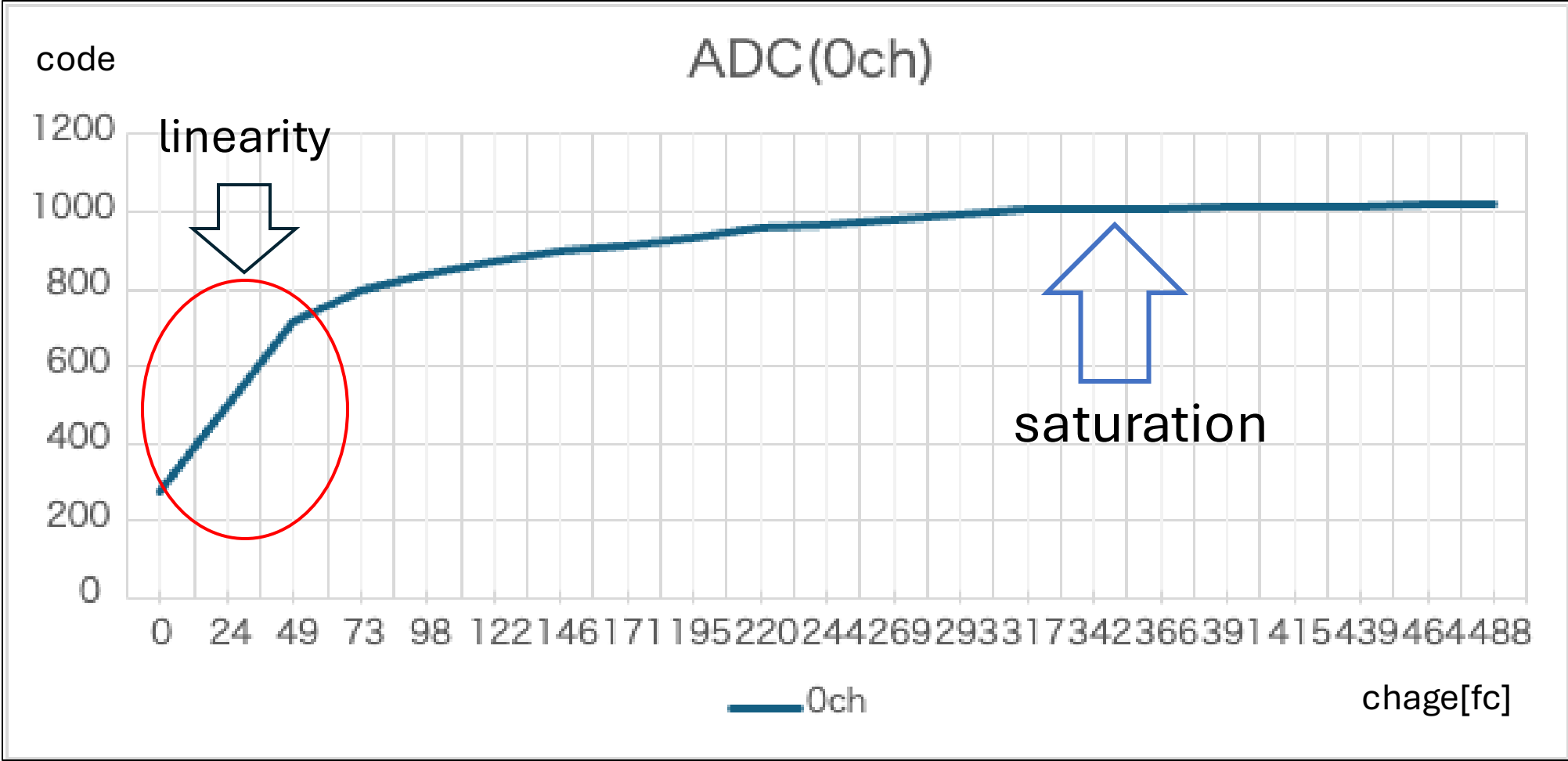




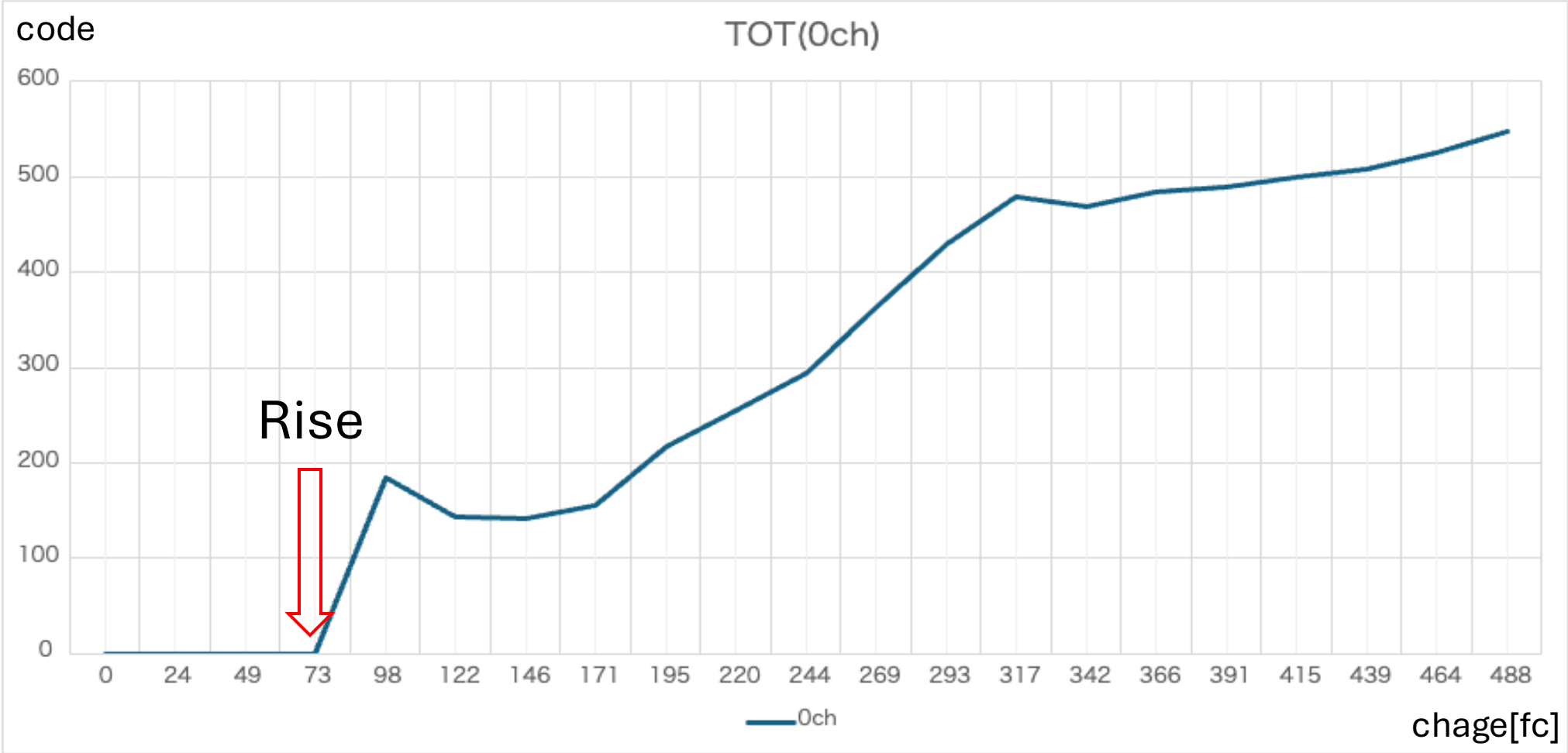
# ADC(0ch)



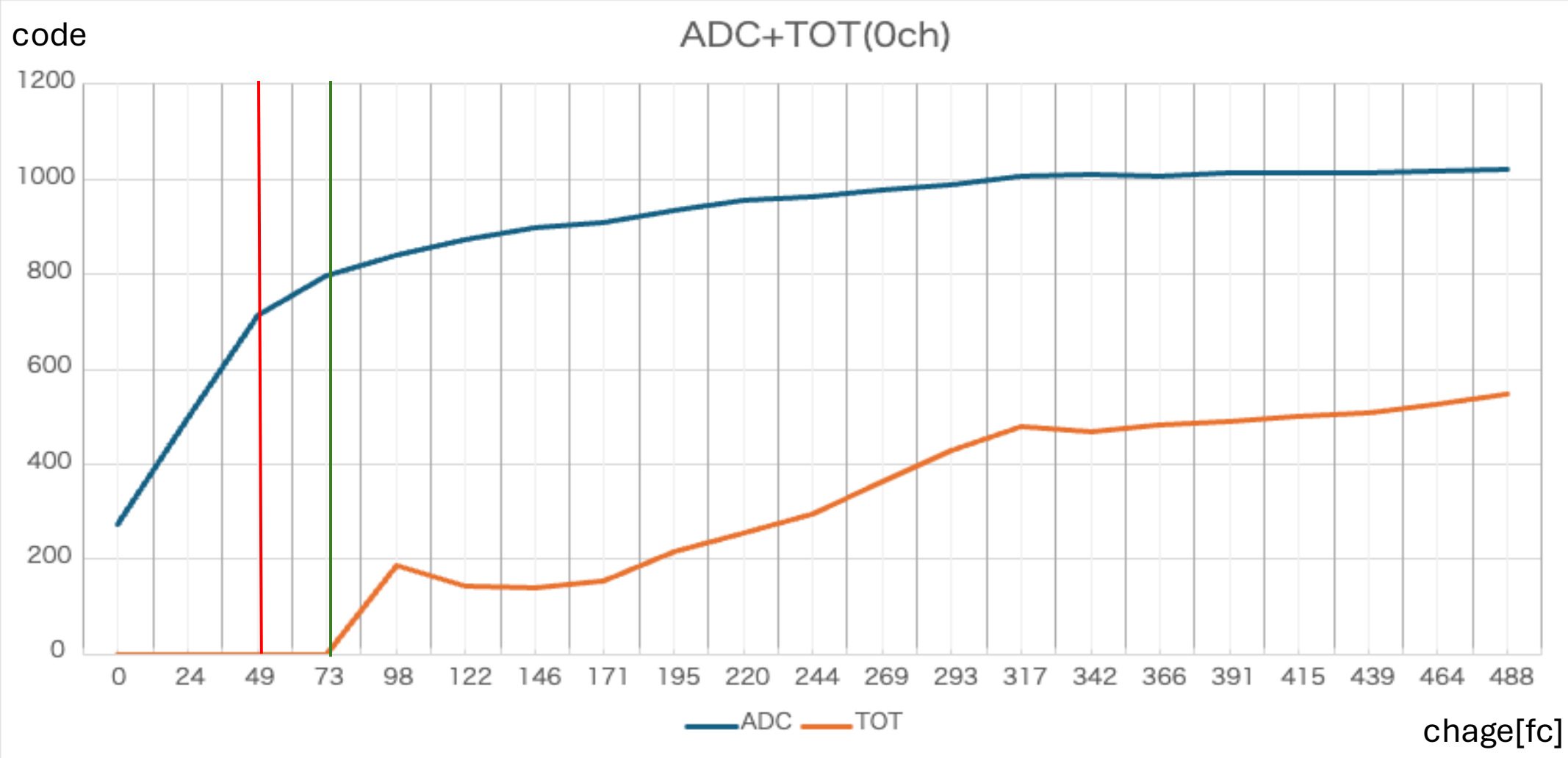
# ADC(0ch)



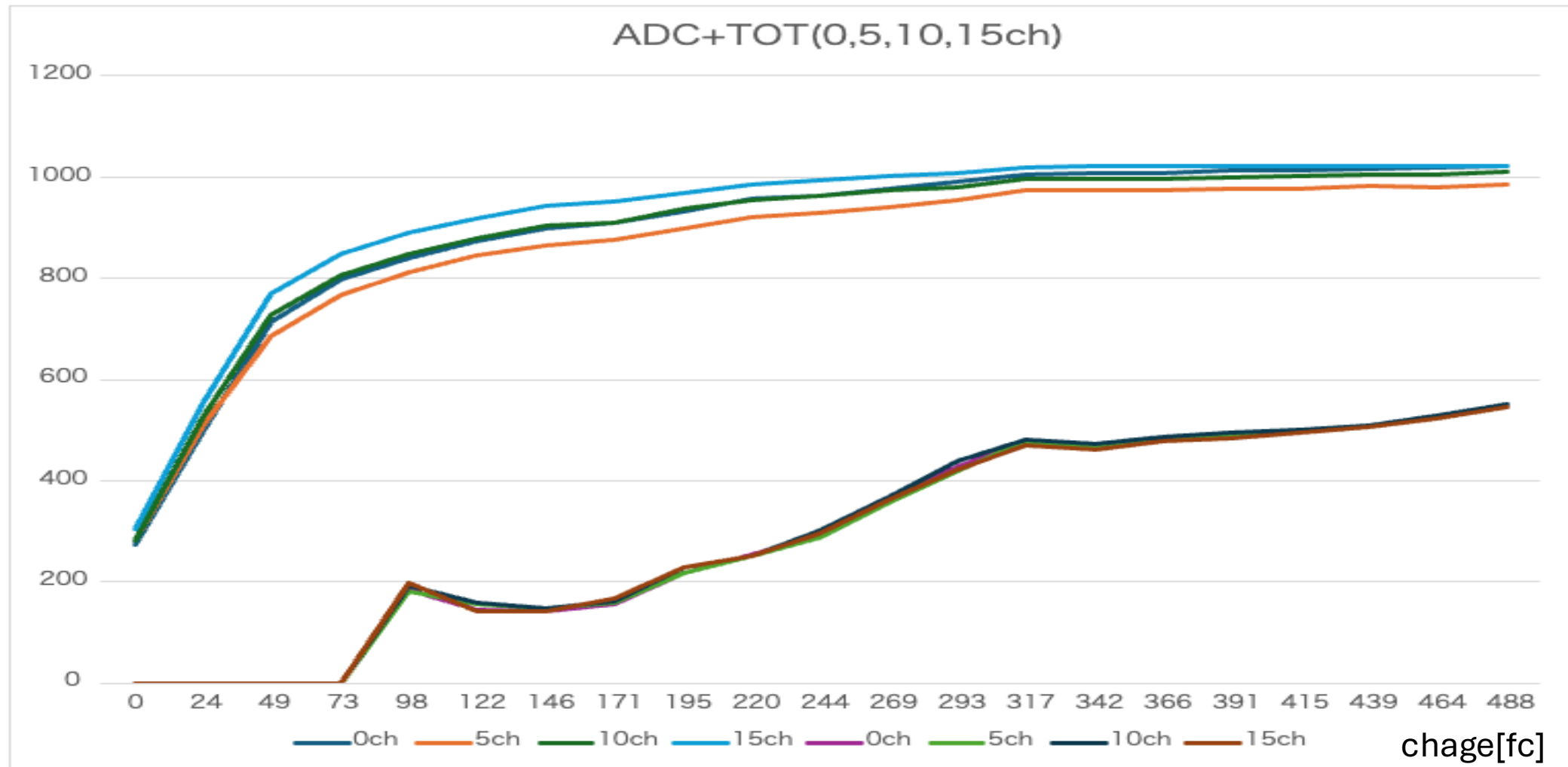
# TOT(0ch)



# ADC+TOT(0ch)



# 0,5,10,15ch





# Summary

- The timing when the ADC loses linearity and the timing when ToT starts are both early.
- The thresholds for ToA and ToT may be inappropriate.

# Plan

- I would like to deepen my understanding of parameter settings during measurements and other related aspects.
- There are about 300 v2 chips, so measurements will be conducted on them.
- Preparation for measuring the v3 chips

**Thank you for your attention**

# TOT (Time Over Threshold)

Threshold A=TOA (Time of Arrive)

Indicates the time when the rising edge of the signal reaches threshold A.

Threshold B=TOT

Indicates the difference between the time when the falling edge of the signal reaches threshold B and the TOA

